## Notice of References Cited Application/Control N 09/754,073 Applicant(s)/Patent Under Reexamination MEIER ET AL. Examiner Crystal J. Barnes Application/Control N Applicant(s)/Patent Under Reexamination MEIER ET AL. Page 1 of 1

## **U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	Α	US-5,987,508	11-1999	Agraharam et al.	709/217
	В	US-6,023,700	02-2000	Owens et al.	707/10
	U	US-6,085,231	07-2000	Agraharam et al.	709/206
	۵	US-6,014,711	01-2000	Brown, Anne R.	709/245
	Ш	US-6,292,799	09-2001	Peek et al.	707/10
	F	US-6,333,973	12-2001	Smith et al.	379/88.12
	G	US-6,356,937	03-2002	Montville et al.	709/206
	Ι	US-6,363,140	03-2002	Pinard, Debbie	379/88.22
	1	US-6,400,810	06-2002	Skladman et al.	379/93.24
	J	US-6,498,797	12-2002	Anerousis et al.	370/522
	К	US-			
	L	US-			
	М	US-			

## **FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
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	Р					
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	Т					

## **NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	US Pub. No. 2002/0176117 A1 to RANDALLi et al.
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	x	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)

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